

## 2021 IEEE International Reliability Physics Symposium - Technical Program

### March 21 - 24th, VIRTUAL

Sunday • March 21						Monday • March 22						Tuesday • March 23						Wednesday • March 24						
Time	Duration	Virtual Kick-off Day1				Time	Duration	Virtual Kick-off Day2				Time	Duration	Virtual Kick-off Day3				Time	Duration	Virtual Kick-off Day4				
8:00 AM	10	GC Welcome & Introduction				8:00 AM	45	Keynote Speaker 2- John Palmour CTO Cree / Wolfspeed				8:00 AM	45	Keynote Speaker 3 - Peter Gammel CTO MWI at Global Foundries				8:00 AM	45	Keynote Speaker 4- Alessandro Piovaccari Silicon				
8:10 AM	10	Overview of Technical Program				8:45 AM	0	3A- PI	3B-5G	Tutorials	Tutorials	8:45 AM	0	4A- CR	4B-RT	Tutorials	Tutorials	8:45 AM	0	5A- TX	5B-EM	5C- SiC	Tutorials	
8:20 AM	15	Awards				8:45 AM	5	Session Intro				8:45 AM	5	Session Intro				8:45 AM	5	Session Intro				
8:35 AM	45	Keynote Speaker 1 - Seok-Hee Lee, CEO SK Hynix				8:50 AM	25	121	invited- JC	Tut5- Neuromorphic Computing	Tut6- Single event displacement Damage	8:50 AM	25	invited- RK	173	Tut12- System focused reliability of SiC Mosfets	Tut13- Hot Carrier Degradation	8:50 AM	25	invited- TBD	invtd- 237	invited- JL	Tut17- EDA Solutions for LU	
9:20 AM	0	2A- GD	2B-GAN	2C- NC	Tutorials	9:15 AM	25	92	invited- MD			9:15 AM	25	166	161			9:15 AM	25	209	invtd- SL	invited- TN		
9:20 AM	5	Session Intro				9:40 AM	25	64	220			9:40 AM	25	202	61			9:40 AM	25	91	invtd- SK	93		
9:25 AM	25	ESREF	invited- SB	invited- DI	TuT1- 3D packaging	10:05 AM	25	126	221	10:05 AM	25	12	84	10:05 AM	25	141	124	31						
9:50 AM	25	56	158	invited-YC		10:30 AM	25			Tut7- LowK dielectric Reliability	Tut8- GaN Reliability	10:30 AM	25	36	115	Tut14- Electromigration Reliability	Tut15- Cryogenic CMOS	10:30 AM	25	85		156		
10:15 AM	25	133	79	105		10:55 AM	25					10:55 AM	25	38	181			10:55 AM	25	67		116		
10:40 AM	25	197	33	169	Q&A	11:20 AM	25					11:20 AM	25	late paper	206			11:20 AM	25	189		144		
11:05 AM	25	14	34	59		11:45 AM	20	Authors' Corner			11:45 AM	20	Authors' Corner			11:45 AM	20	Authors' Corner						
11:30 AM	30	Authors' Corner				12:05 PM	175	Lunch (180 min)				12:05 PM	175	Lunch (180 min)				12:05 PM	175	Lunch (180 min)				
12:00 PM	180	Lunch (180 min)				3:00 PM	0	Welcome back				3:00 PM	0	Welcome back				3:00 PM	0	Welcome back				
3:00 PM	0	Welcome back				3:00 PM	0	3D-SY/SE	3E-5G	3F- MB	Tutorials	3:00 PM	0	4D- PK	4E- RT	Tutorials	Tutorials	3:00 PM	0	5D-EM	Tutorials			
3:00 PM	0	2D- NC	Tutorials	Tutorials	Tutorials	3:00 PM	5	Session Intro			Tut9- High-k dielectrics on Non Silicon Semiconductors	3:00 PM	5	Session Intro			3:00 PM	5	Session Intro					
3:00 PM	5	Session Intro				3:05 PM	25	invited-235	invited- SP	invited-183		3:05 PM	25	invited- JO	139	3:05 PM	25	invited- TM	Tut19-Exploring Relation of ESD and EMC;					
3:05 PM	25	invited- RW	Tut2- Bayesian Stats	Tut3- Rel. Testing	Tut4- 5G/mmW/RF	3:30 PM	25	200	invited- JS	87		3:30 PM	25	29		3:30 PM	25	invited- SS				Tut20- Full Chip ESD Ver.		
3:30 PM	25	192				3:55 PM	25	32	137	66	3:55 PM	25	142		3:55 PM	25	43	Tut20- Full Chip ESD Ver.						
3:55 PM	25	159				4:20 PM	25	113	168	152	4:20 PM	25	163		4:20 PM	25	47				Tut20- Full Chip ESD Ver.			
4:20 PM	25	182	Q&A			4:45 PM	25	136		147	4:45 PM	25			4:45 PM	25	98							Tut20- Full Chip ESD Ver.
4:45 PM	25	Authors' Corner				5:10 PM	20	Authors' Corner			5:10 PM	0	WORKSHOPS				5:10 PM	20	Authors' Corner					
5:10 PM	0	Reliability Year in Review				5:30 PM	0	3G- PR/ESD	3H-MY	3I-MB	5:05 PM	50	Device	SSD	BEOL	GaN	Neuromorphic	ESD	5:30 PM	120	POSTERS			
5:10 PM	5	Introduction				5:30 PM	5	Session Intro			5:55 PM	10	Break 10 min				7:30 PM	15	size drawing, wrap up for IRPS 2021 and opening of IRPS 2022					
5:15 PM	45	Transistor - FinFET vs Nanosheet				5:35 PM	25	83	invited- KI	104	6:05 PM	50	Circuit	Emerging Mem	Automotive	SiC	Rf/mmW/5G							
6:00 PM	45	Reliability Testing				6:00 PM	25	178	45		6:55 PM	0	Closing for day											
6:45 PM	45	ESD/LU				6:25 PM	25	179	110															
7:30 PM	0	YIR Questions				6:50 PM	20	Authors' Corner																
7:30 PM	0	Closing for day				7:10 PM	0	Closing for day																

PK - 3D/2.5D/Packaging	PR - IC Product Rel
CR- Circuit Reliability	RT - Reliability Testing
GD - Gate/MOL Diel	SE - Soft Errors
EL - ESD/Latch-Up	SY - System Reliability
FA - Failure Analysis	TX - Transistors
MY - Memory	GaN - Wide Bandgap
MB - Metal/Back-End	NC - Neuromorphic
PI - Process Integration	EM- Emerging Memory
5G - RF/mmW/5G Reliability	SiC- Wide Bandgap